SW2N60DC-VB TO251

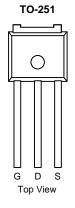


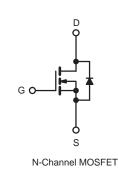
SW2N60DC-VB TO251 Datasheet **Power MOSFET**

PRODUCT SUMMARY					
V _{DS} (V)	600				
R _{DS(on)} (Ω)	$V_{GS} = 10 V$ 4.4				
Q _g (Max.) (nC)	18				
Q _{gs} (nC)	3.0				
Q _{gd} (nC)	8.9				
Configuration	Sing	le			

FEATURES

- Halogen-free According to IEC 61249-2-21 Definition
- Dynamic dV/dt Rating
- Repetitive Avalanche Rated
- Surface Mount (IRFRC20, SiHFRC20)
- Straight Lead (IRFUC20, SiHFUC20)
- Available in Tape and Reel
- Fast Switching
- Ease of Paralleling
- Compliant to RoHS Directive 2002/95/EC





PARAMETER			SYMBOL	LIMIT	UNIT	
Drain-Source Voltage			V _{DS}	600	- V	
Gate-Source Voltage			V _{GS}	± 20		
Continuous Drain Current	V _{GS} at 10 V	T _C = 25 °C	1-	2.0	A	
Continuous Drain Current		T _C = 100 °C	ID	1.3		
Pulsed Drain Current ^a			I _{DM}	8.0	1	
Linear Derating Factor				0.33	W/°C	
Linear Derating Factor (PCB Mount) ^e			-	0.020	W/ C	
Single Pulse Avalanche Energy ^b			E _{AS}	74	mJ	
Repetitive Avalanche Current ^a			I _{AR}	2.0	А	
Repetitive Avalanche Energy ^a			E _{AR}	4.2	mJ	
Maximum Power Dissipation	T _C = 25 °C		D	42	w	
Maximum Power Dissipation (PCB Mount) ^e	T _A = 25 °C		P _D	2.5	- VV	
Peak Diode Recovery dV/dt ^c			dV/dt	3.0	V/ns	
Operating Junction and Storage Temperature Range			T _J , T _{stg}	- 55 to + 150	°C	
oldering Recommendations (Peak Temperature) for 10 s			260 ^d			

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. $V_{DD} = 50 \text{ V}$, starting $T_J = 25 \text{ °C}$, L = 37 mH, $R_g = 25 \Omega$, $I_{AS} = 2.0 \text{ A}$ (see fig. 12). c. $I_{SD} \le 2.0 \text{ A}$, dl/dt $\le 40 \text{ A/}\mu\text{s}$, $V_{DD} \le V_{DS}$, $T_J \le 150 \text{ °C}$. d. 1.6 mm from case. e. When mounted on 1" square PCB (FR-4 or G-10 material).

* Pb containing terminations are not RoHS compliant, exemptions may apply

Available



THERMAL RESISTANCE RAT	HERMAL RESISTANCE RATINGS				
PARAMETER	SYMBOL	MIN.	TYP.	MAX.	UNIT
Maximum Junction-to-Ambient	R _{thJA}	-	-	110	
Maximum Junction-to-Ambient (PCB Mount) ^a	R _{thJA}	-	-	50	°C/W
Maximum Junction-to-Case (Drain)	R _{thJC}	-	-	3.0	

Note

a. When mounted on 1" square PCB (FR-4 or G-10 material).

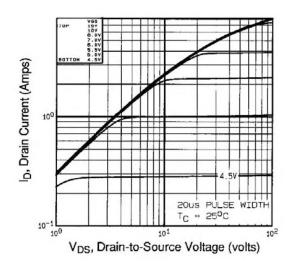
PARAMETER	SYMBOL	TEST CONDITIONS MI			TYP.	MAX.	UNIT
Static							•
Drain-Source Breakdown Voltage	V _{DS}	V _{GS} =	= 0 V, I _D = 250 μA	600	-	-	V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_J$	Reference to 25 °C, I _D = 1 mA		-	0.88	-	V/°C
Gate-Source Threshold Voltage	V _{GS(th)}	V _{DS} =	= V _{GS} , I _D = 250 μΑ	2.0	-	4.0	V
Gate-Source Leakage	I _{GSS}	V _{GS} = ± 20 V		-	-	± 100	nA
		V _{DS} = 600 V, V _{GS} = 0 V		-	-	100	
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = 480 V	∕, V _{GS} = 0 V, T _J = 125 °C	-	-	500	μA
Drain-Source On-State Resistance	R _{DS(on)}	V _{GS} = 10 V	I _D = 1.2 A ^b	-	4.4	-	Ω
Forward Transconductance	g _{fs}	V _{DS} :	= 50 V, I _D = 1.2 A	1.4	-	-	S
Dynamic							
Input Capacitance	C _{iss}		$V_{GS} = 0 V$,	-	350	-	
Output Capacitance	Coss		$V_{GS} = 0 V,$ $V_{DS} = -25 V,$		48	-	pF
Reverse Transfer Capacitance	C _{rss}	f = 1.	0 MHz, see fig. 5	-	8.6	-	
Total Gate Charge	Qg			-	-	18	
Gate-Source Charge	Q _{gs}	$V_{GS} = 10 V$	$I_D = 2.0 \text{ A}, V_{DS} = 360 \text{ V},$ see fig. 6 and 13^{b}	-	-	3.0	nC
Gate-Drain Charge	Q _{gd}]		-	-	8.9	
Turn-On Delay Time	t _{d(on)}			-	10	-	
Rise Time	t _r	V _{DD} =	300 V, I _D = 2.0 A,	-	23	-	
Turn-Off Delay Time	t _{d(off)}	$R_g = 18 \Omega$,	$R_D = 135 \Omega$, see fig. 10^{b}	-	30	-	ns
Fall Time	t _f]		-	25	-	
Internal Drain Inductance	L _D	Between lead 6 mm (0.25") f	rom	-	4.5	-	nH
Internal Source Inductance	Ls	die contact		-	7.5	-	
Drain-Source Body Diode Characteristic	S						
Continuous Source-Drain Diode Current	I _S	MOSFET symbol showing the		-	-	2.0	А
Pulsed Diode Forward Current ^a	I _{SM}	integral revers p - n junction		-	-	8.0	
Body Diode Voltage	V_{SD}	T _J = 25 °C	, $I_{\rm S}$ = 2.0 A, $V_{\rm GS}$ = 0 V ^b	-	-	1.6	V
Body Diode Reverse Recovery Time	t _{rr}	T 25 °C I	= 2.0 A, dl/dt = 100 A/µs ^b	-	290	580	ns
Body Diode Reverse Recovery Charge	Q _{rr}	$I_{\rm J} = 25$ C, I _F	$-2.0 \text{ A}, \text{ u/ut} = 100 \text{ A/}\mu\text{S}^{\circ}$	-	0.67	1.3	μC
Forward Turn-On Time	t _{on}	Intrinsic tu	rn-on time is negligible (turn	-on is dor	ninated b	$v L_s$ and	L _D)

Notes

a. Repetitive rating; pulse width limited by maximum junction temperature (see fig. 11). b. Pulse width \leq 300 µs; duty cycle \leq 2 %.

SW2N60DC-VB TO251





TYPICAL CHARACTERISTICS 25 °C, unless otherwise noted



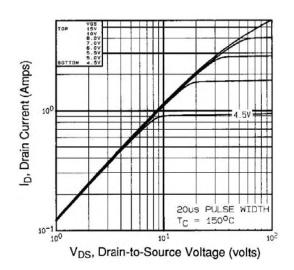


Fig. 2 - Typical Output Characteristics, $T_C = 150 \ ^{\circ}C$

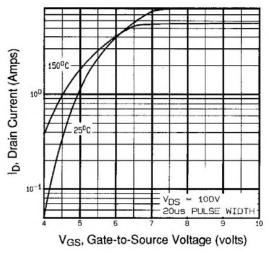


Fig. 3 - Typical Transfer Characteristics

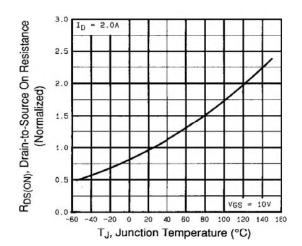


Fig. 4 - Normalized On-Resistance vs. Temperature



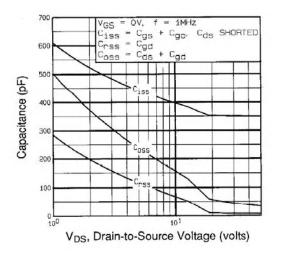
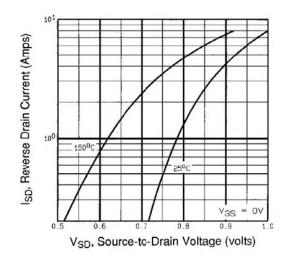


Fig. 5 - Typical Capacitance vs. Drain-to-Source Voltage





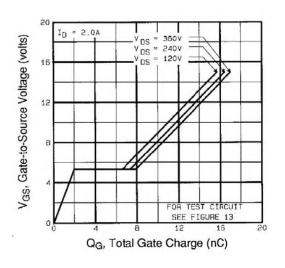


Fig. 6 - Typical Gate Charge vs. Gate-to-Source Voltage

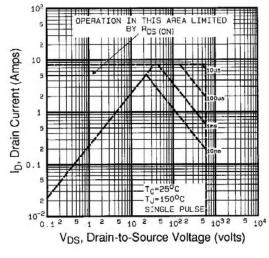


Fig. 8 - Maximum Safe Operating Area



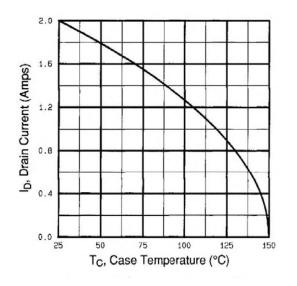


Fig. 9 - Maximum Drain Current vs. Case Temperature

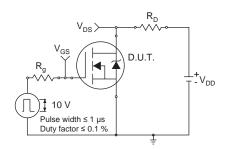


Fig. 10a - Switching Time Test Circuit

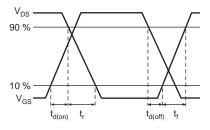
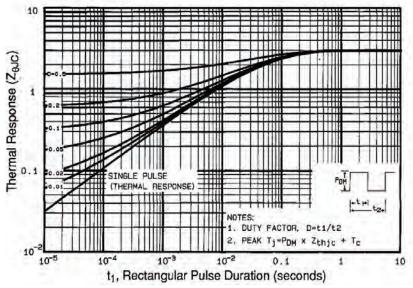


Fig. 10b - Switching Time Waveforms







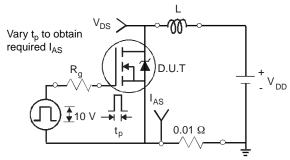


Fig. 12a - Unclamped Inductive Test Circuit

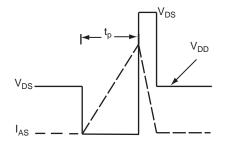


Fig. 12b - Unclamped Inductive Waveforms

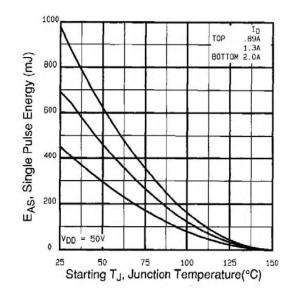


Fig. 12c - Maximum Avalanche Energy vs. Drain Current

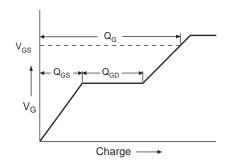


Fig. 13a - Basic Gate Charge Waveform

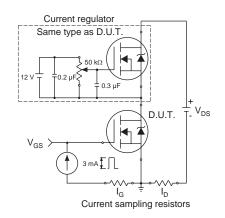
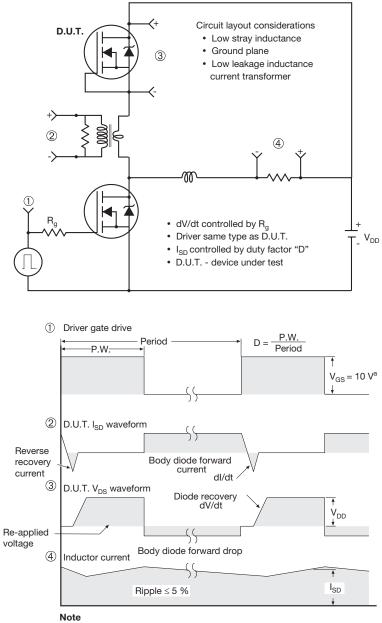


Fig. 13b - Gate Charge Test Circuit



Peak Diode Recovery dV/dt Test Circuit



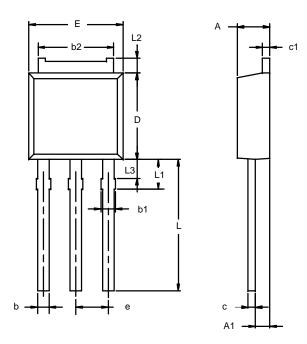
a. V_{GS} = 5 V for logic level devices

Fig. 14 - For N-Channel

SW2N60DC-VB TO251



TO-251AA (DPAK)



Note: Dimension L3 is for reference only.

	MILLIN	IETERS	INC	HES
Dim	Min	Max	Min	Max
Α	2.21	2.38	0.087	0.094
A1	0.89	1.14	0.035	0.045
b	0.71	0.89	0.028	0.035
b1	0.76	1.14	0.030	0.045
b2	5.23	5.43	0.206	0.214
С	0.46	0.58	0.018	0.023
c1	0.46	0.58	0.018	0.023
D	5.97	6.22	0.235	0.245
Е	6.48	6.73	0.255	0.265
е	2.28	BSC	0.090	BSC
L	8.89	9.53	0.350	0.375
L1	1.91	2.28	0.075	0.090
L2	0.89	1.27	0.035	0.050
L3	1.15	1.52	0.045	0.060
ECN: S-03 DWG: 53	3946—Rev. E 46	, 09-Jul-01		



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